

**Search Notes**

Application/Control No.

10/010,779

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under  
Reexamination

EISENSTEIN, JONATHAN

Art Unit

3629

**SEARCHED**

Class	Subclass	Date	Examiner
705	1	4/06 2011	
6			
7			
8			
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10			
26		✓	✓

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I US	4/06 2011	
Patent PG Pub		
II FOREIGN		
1. EPO 2 - JPO 3 - Devent		
4. FISM-TDB	✓	✓

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner